TOSHIBA Transistor Silicon NPN Epitaxial Planar Type

2SC4321

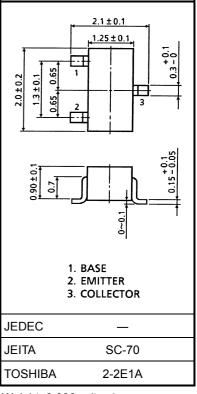
VHF~UHF Band Low Noise Amplifier Applications

Unit: mm

- Low noise figure, high gain.
- NF = 1.1dB, $|S_{21e}|^2 = 13dB$ (f = 1 GHz)

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit	
Collector-base voltage	V_{CBO}	20	V	
Collector-emitter voltage	V _{CEO}	10	V	
Emitter-base voltage	V _{EBO}	1.5	٧	
Base current	Ι _Β	20	mA	
Collector current	I _C	40	mA	
Collector power dissipation	P _C	100	mW	
Junction temperature	Tj	125	°C	
Storage temperature range	T _{stg}	−55~125	°C	



Weight: 0.006 g (typ.)

Microwave Characteristics (Ta = 25°C)

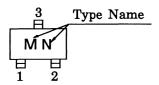
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Transition frequency	f _T	$V_{CE} = 8 \text{ V}, I_{C} = 20 \text{ mA}$	7	10	_	GHz	
Insertion gain	S _{21e} ² (1)	1) $V_{CE} = 8 \text{ V}, I_{C} = 20 \text{ mA}, f = 1 \text{ GHz}$ 10			_	dB	
	S _{21e} ² (2)	$V_{CE} = 8 \text{ V}, I_{C} = 20 \text{ mA}, f = 2 \text{ GHz}$	_	7	_	ub	
Noise figure	NF (1)	$V_{CE} = 8 \text{ V}, I_{C} = 5 \text{ mA}, f = 1 \text{ GHz}$	_	1.1	2.5	5 dB	
Noise ligure	NF (2)	$V_{CE} = 8 \text{ V}, I_{C} = 5 \text{ mA}, f = 2 \text{ GHz}$		1.7		uБ	

Electrical Characteristics (Ta = 25°C)

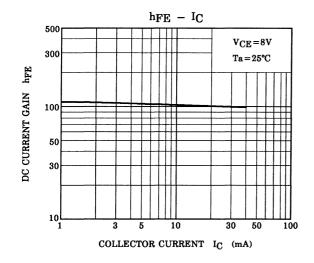
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I _{CBO}	$V_{CB} = 10 \text{ V}, I_{E} = 0$	_	_	1	μΑ
Emitter cut-off current	I _{EBO}	V _{EB} = 1 V, I _C = 0	_	_	1	μΑ
DC current gain	h _{FE}	$V_{CE} = 8 \text{ V}, I_{C} = 20 \text{ mA}$	50	_	250	
Output capacitance	C _{ob}	V _{CB} = 10 V, I _E = 0, f = 1 MHz (Note)	_	0.65	_	pF
Reverse transfer capacitance	C _{re}	VCB = 10 V, 1E = 0, 1 = 1 WILLZ (NOTE)	_	0.45	0.9	pF

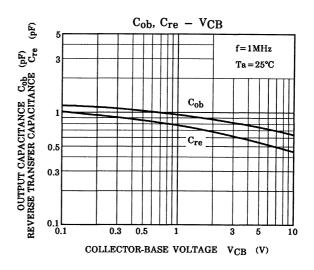
Note: C_{re} is measured by 3 terminal method with capacitance bridge.

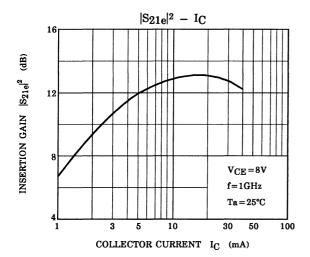
Marking

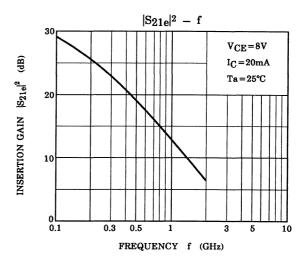


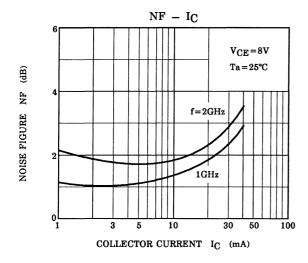
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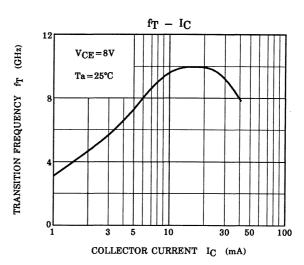




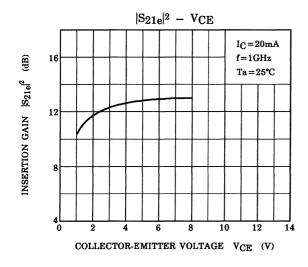


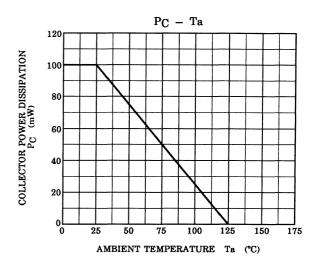






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S-Parameter $Z_O = 50 \Omega$, Ta = 25°C

$V_{CE} = 8 V$, $I_C = 5 mA$

Frequency	S11		S21		S12		S22	
MHz	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
200	0.680	-49.6	11.448	140.0	0.048	67.0	0.820	-28.4
400	0.478	-83.2	8.076	116.6	0.073	59.6	0.613	-41.1
600	0.353	-108.3	5.992	102.7	0.092	59.1	0.495	-46.2
800	0.281	-129.2	4.711	93.0	0.109	60.1	0.428	-48.9
1000	0.240	-149.0	3.875	85.8	0.127	61.1	0.389	-51.0
1200	0.216	-169.1	3.294	79.6	0.146	62.1	0.364	-53.3
1400	0.202	175.1	2.876	73.8	0.166	62.6	0.350	-55.6
1600	0.194	158.9	2.572	69.0	0.186	62.6	0.339	-58.4
1800	0.193	142.9	2.349	64.5	0.207	62.4	0.332	-61.7
2000	0.202	130.9	2.128	61.1	0.227	62.3	0.325	-65.7

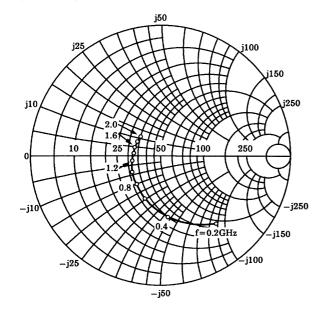
$V_{CE} = 8 V$, $I_C = 20 mA$

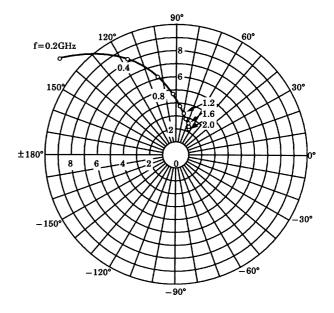
Frequency	S11		S21		S12		S22	
MHz	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
200	0.332	-83.7	18.406	118.0	0.034	68.8	0.565	-38.2
400	0.212	-123.3	10.378	100.0	0.057	71.1	0.393	-39.9
600	0.173	-150.7	7.130	90.7	0.080	73.0	0.336	-39.3
800	0.157	-175.3	5.442	84.3	0.104	73.0	0.309	-39.6
1000	0.161	167.5	4.394	79.1	0.128	72.4	0.295	-41.0
1200	0.162	149.7	3.728	74.3	0.152	71.7	0.285	-43.2
1400	0.169	138.2	3.240	69.5	0.175	70.5	0.280	-46.0
1600	0.177	125.9	2.877	65.7	0.200	68.9	0.278	-48.9
1800	0.178	113.5	2.595	61.8	0.223	67.4	0.279	-53.0
2000	0.190	104.3	2.352	58.6	0.246	65.8	0.275	-57.8

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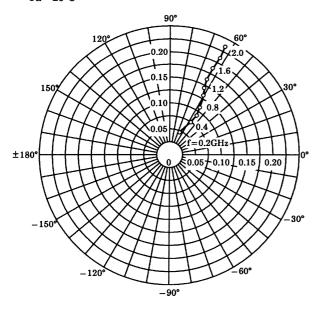
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 5mA \\ Ta = 25^{\circ}C \\ (UNIT:\Omega) \end{array}$



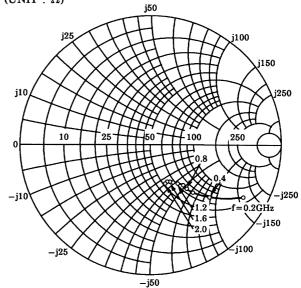




 S_{12e} $V_{CE}=8V$ $I_{C}=5mA$ $T_{a}=25^{\circ}C$

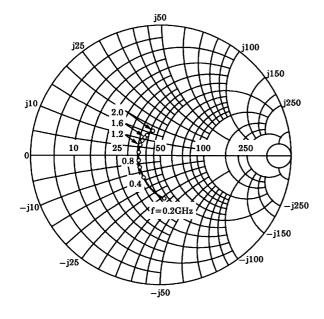


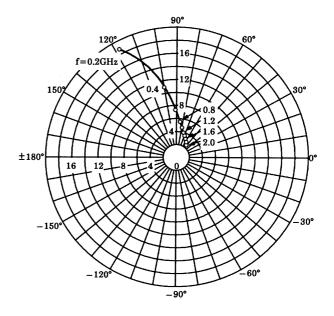
 $\begin{array}{l} S_{22e} \\ V_{CE} = 8V \\ I_{C} = 5mA \\ T_{a} = 25^{\circ}C \\ (UNIT:\Omega) \end{array}$



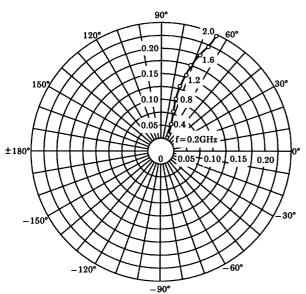
 $\begin{array}{l} S_{11e} \\ V_{CE} = 8V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \\ (UNIT:\Omega) \end{array}$



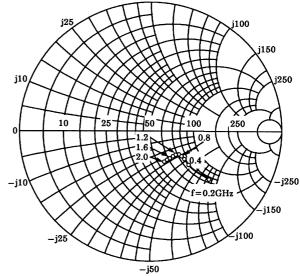




 S_{12e} $V_{CE}=8V$ $I_{C}=20$ mA $T_{a}=25$ °C



S22e VCE=8V IC=20mA $Ta=25^{\circ}C$ $(UNIT:\Omega)$



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